Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2660	scan chain$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2004/12/26 11:22
L2	2965	circuit under test	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2004/12/26 11:22
L4	35	compressed test pattern$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2004/12/26 11:22
L5	12	decompressed test pattern$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2004/12/26 11:22
L6	214	l1 and l2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2004/12/26 11:23
L7	11	l4 and l5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2004/12/26 11:23
L8	8	l7 and l6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2004/12/26 11:23
L9	33	linear finite state machine	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2004/12/26 11:24

L10	6	I8 and I9	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2004/12/26 11:24